Parts and Material Analysis Report

		•	-
Customer	Technology Solutions Ltd	Part Number	PEX8613-BA50BIG
Customer PO	1628-A	Manufacturer	BROADCOM
Customer Address	6 Odem Street, Petach Tikva 4951789 Israel	Date/Lot Code	1505
Report Date	7/18/2018 5:32:12 PM	Quantity Revd	total: 2 test: 2
Revision	0	TS WO #	W1807120002

Summary Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

Test Quantity	Result	Comments
I	Documentation of	& Packaging (AS6081, Section 4.2.6.4.1)
1	С	
1	С	
	General Visual	Inspection (AS6081, Section 4.2.6.4.2.1)
1	С	
	Detailed Visual	Inspection (AS6081, Section 4.2.6.4.2.2)
2	С	
2	С	
2	С	
	Re-Marking/Re-S	Surfacing Test (AS6081, Section 4.2.6.4.3)
1	С	
1	С	
1	С	
1	С	
	X-Ray Ins _l	pection (AS6081, Section 4.2.6.4.4)
2	С	
	XRF Eval	uation (AS6081, Section 4.2.6.4.5)
2	С	
	Internal Visual	Inspection (AS6081, Section 4.2.6.4.6)
1	С	
	Electrical	Testing (TS 622-001 Section 8.0)
NA	NA	
	Soldera	bility Test (JEDEC J-STD-02)
	NA	
	Ba	king (JEDEC J-STD-033)
	NA	
		Tape and Reel
	NA	
	1 1 1 2 2 2 2 2 1 1 1 1 1 1 1 2 2 2 2 1	Documentation 1 C 1 C 1 C Detailed Visual 1 C 2 C 2 C 2 C 2 C 2 C 1 C 2 C 1 C 1 C 1 C 1 C 1 C 1 C 1 C 1 C 1 C 1 C 2 C XRF Eval C 2 C Internal Visual Internal Visual 1 C 1 C NA NA NA NA NA NA NA NA NA NA <tr t=""> NA <td< td=""></td<></tr>

Assessment

No non-conformities observed.

Analysis Summary

External Visual Inspection

External Visual Inspection on (2) sample(s) marked with D/C: 1505 revealed legible device markings consistent with the lot traveler and published data related to the part. No secondary coating, sanding marks, cracks, or chips were observed on all devices inspected. Leads were in acceptable condition.

Device package characteristics and dimensions matched manufacturer's specification.

No records of suspect counterfeit parts were found for this part number in the ERAI/GIDEP data bases.

NOTE: All inspections in this section performed in accordance with VÙ Test Procedure Manual, 622-001, Sections 1-3; microscope magnification = 10X to 30X unless otherwise noted.

Internal Visual Inspection

Internal Visual Inspection on (1) sample(s) marked with D/C: 1505 revealed markings PEX8618-Bx marked on the die. Die marking correlated with device's external marking.

No information in the VÙ die bank data base for this part number.

Testing performed in accordance with VÙ Test Procedure Manual, 622-001, Section 4

X-Ray Inspection

X-Ray Analysis of (2) random sample(s) revealed the same internal structure on all the samples. No internal damages were observed during inspection.

X-Ray inspection performed in accordance with VÙ Test Procedure Manual, 622-001, Section 5

Dosage = 80 kEV, Exposure = 3 Seconds

Represented images are typical. All images are available on request.

XRF Test

XRF Analysis performed on (2) random sample(s) revealed the devices are not RoHS Compliant.

NOTE: Niton XL3t XRF spectrometer analyzers do not conclusively measure the elemental composition of any samples but do measure the % of each element relative to the others being measured. No comparison to actual manufacturer composition declarations should be made or implied.

XRF testing performed in accordance with VÙ Test Procedure Manual, 622-001, Section 6

Solvent Test

Marking Permanency Test results were negative - no markings were removed.

Acetone Test results for resurfacing were negative - no residue was deposited on the swab.

HCT-1 Test results for resurfacing were negative - no residue was deposited on the swab. (Part markings only were removed)

HCT-2 Test results for resurfacing were negative - no residue was deposited on the swab.

Acetone Test results for resurfacing were negative - no residue was deposited on the swab.

HCT-1 Test results for resurfacing were negative - no residue was deposited on the swab. (Part markings only were removed)

HCT-2 Test results for resurfacing were negative - no residue was deposited on the swab.

Note: HCT-1: 1-Methyl 2-Pyrrolidinone; HCT-2: Dynasolve 715

Testing performed in accordance with VÙ

Test Procedure Manual, 622-001, Section 3

Device Description

Device	PCIe Gen 2, 5.0GT/s 12-lane, 3-part Switch
	PCN Obsolescence/ EOLOBS 15/Aug/2015Moisture Sensitivity Level (MSL)3 (168 Hours)Package:324 FBGA (19 x 19 mm)
Case	324-Pin FBGA
PDF	https://www.usbid.com/assets/datasheets/4E/pex8613-ba50big.pdf
Datasheet	ΝΑ

Receiving - Documentation and Package Inspection

Detailed Criteria: Per AS6081 4.2.6.4.2.1

Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

Date	Weight	ESD Bag	Date/Lot Code	Part Count	Vacuum Sealed	Carrier Type	Moisture protection
7/12/2018 12:00:06 PM	1.0000 lbs	Not Present	1505	2		Bulk	Not Present

Criteria	Result	Comments
Receiving - Doc	umentation	and Package Inspection
Lot/Date Code information consistent with published data	С	
Manufacturer label/logo are present and matches datasheet and prev orders	С	
Documentation review	С	
Barcode data scans and matches	NA	
Consistent package materials	С	
Ger	neral Visual	Inspection
Parts received in a single shipment	С	
Consistent part markings throughout lot	С	
Consistent appearance	С	
Consistent handling, packaging and storage	С	
No evidence parts have been separated	С	

Box received in acceptable condition.

Devices were received in acceptable condition.

Part markings were consistent throughout the samples inspected and did match customer order information.





Incoming Box

Package Condition

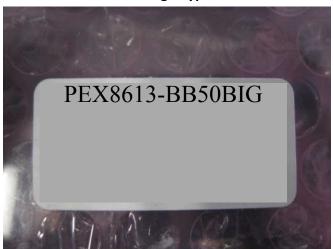
Receiving Inspection (Continued)



Package Type



Package



Label



2 Devices Received

Detailed External Visual Inspection

Detailed Criteria: Per AS6081 4.2.6.4.2.2

Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

Criteria	Sample Size	Result	Comments
		Gen	eral Conditions
Pin/Lead Count	2	С	324
Package Type	2	С	BGA
Verify Pin 1 placement	2	С	
Part Markings	2	С	
Package Conditions	2	С	
Mold Cavities	2	NA	
Plating	2	С	
Lead/Ball Conditions	2	С	
Dimensions	2	С	
GIDEP Verification	2	С	
ERAI Verification	2	С	

External Visual Inspection on (2) sample(s) marked with D/C: 1505 revealed legible device markings consistent with the lot traveler and published data related to the part. No secondary coating, sanding marks, cracks, or chips were observed on all devices inspected. Leads were in acceptable condition.

Device package characteristics and dimensions matched manufacturer's specification.

No records of suspect counterfeit parts were found for this part number in the ERAI/GIDEP data bases.

NOTE: All inspections in this section performed in accordance with TS Test Procedure Manual, 622-001, Sections 1-3; microscope magnification = 10X to 30X unless otherwise noted.

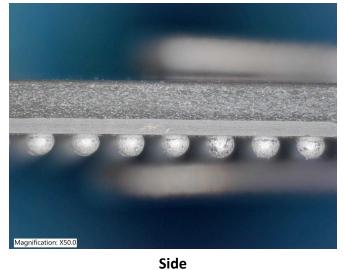


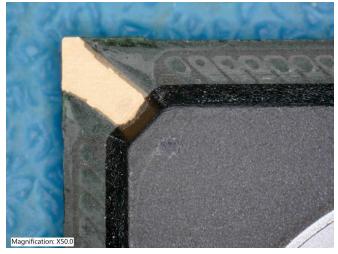


Тор

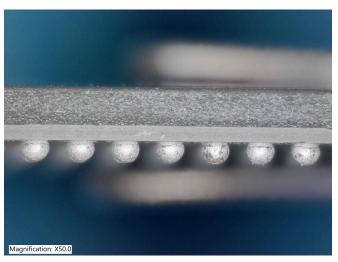
Bottom

Detailed External Visual Inspection (Continued)

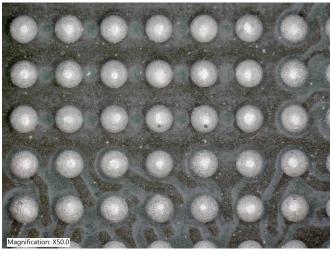




Top Pin



Leads View 1



Leads View 2



Length (19 BSC)



Width (19 BSC)

Detailed External Visual Inspection (Continued)



Thickness (2.2 MAX)

Solvent/Chemical Testing

Inspection for Remarking and Resurfacing Per AS6081 4.2.6.4.3

Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

Criteria	Sample Size	Result	Comments
Marking Permanency	1	С	
Acetone Swab Test	1	С	
HCT-1 (1-Methyl, 2-Pyrrolidione)	1	С	
HCT-2 (Dynasolve 750)	1	С	

Marking Permanency Test results were negative - no markings were removed.

Acetone Test results for resurfacing were negative - no residue was deposited on the swab.

HCT-1 Test results for resurfacing were negative - no residue was deposited on the swab. (Part markings only were removed) HCT-2 Test results for resurfacing were negative - no residue was deposited on the swab.

Note: HCT-1: 1-Methyl 2-Pyrrolidinone; HCT-2: Dynasolve 715

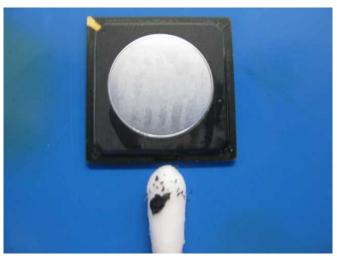
Testing performed in accordance with TS Test Procedure Manual, 622-001, Section 3



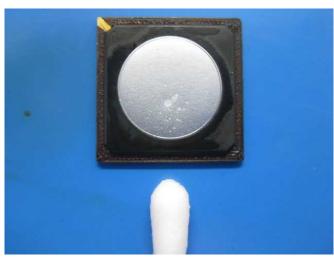


After Permanency

After Acetone



After HCT-1



After HCT-2

Internal Visual Inspection

Internal Analysis Per AS6081 4.2.6.4.3

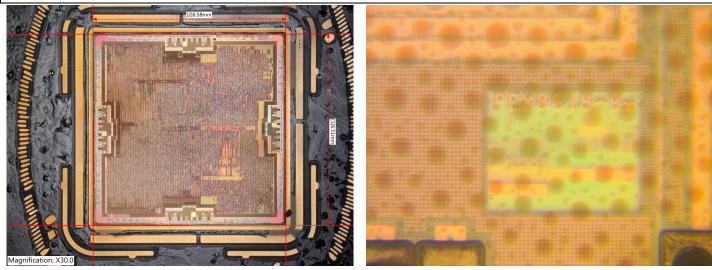
Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

Criteria	Sample Size	Result	Comments
Die Verification	1	NA	
Observed Defects	1	С	
Topography/Markings Match "Known Good" or TS Data Base	1	NA	

Internal Visual Inspection on (1) sample(s) marked with D/C: 1505 revealed markings PEX8618-Bx marked on the die. Die marking correlated with device's external marking.

No information in the TS die bank data base for this part number.

Testing performed in accordance with TS Test Procedure Manual, 622-001, Section 4



Die Topography

Die Markings

X-Ray Inspection

X-Ray Inspection Per AS6081 4.2.6.4.4

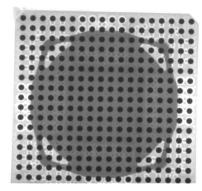
Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

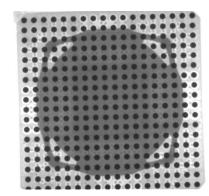
Criteria	Sample Size	Result	Comments
Consistent Internal Contents	2	С	
Consistent Dosage & Exposure Time	2	С	Dosage = 80kEV, Exposure = 3 Seconds
X-Ray Analysis of (2) random sample(s) revealed during inspection.	ed the same	e internal stru	icture on all the samples. No internal damages were observed

X-Ray inspection performed in accordance with TS Test Procedure Manual, 622-001, Section 5

Dosage = 80 kEV, Exposure = 3 Seconds

Represented images are typical. All images are available on request.





X-Ray Analysis - Sample 1

X-Ray Analysis - Sample 2

XRF Inspection

Lead Finish Inspection Per AS6081 4.2.6.4.5

Result: C: Conforming, NC: Non Conforming, S: Suspect, NA: Not Applicable

Criteria	Sample Size	Result	Comments
Consistent Lead Finish per Published Data	2	С	
	ers do not co	onclusively mea	re not RoHS Compliant. sure the elemental composition of any samples but do measure son to actual manufacturer composition declarations should be
XRF testing performed in accordance with TS	Test Proce	dure Manual, 62	22-001, Section 6

XRF Inspection (Continued)

Certificate of Verification

Readin	an No	6038	
Mode			ics Metals
Time			-18 10:07
Duratie	00	60.67	10 10.07
Units	818 (ppm	
	Value	2	
Seque		Final	
Alloy1			h : *7.32
Result		Fail	10.8 S.08 MIR 10
Flags			
SAMPL	E.	PEX8613	3-BA5081G
HEAT		Technolo	ogy Solutions
LOT		W18071	20002
BATCH	4		
MISC		JL	
NOTE		Sample	1
		t 63	5200043
	ppm	*	Error
Cd	1.00		115 250
Pb	< LOD		446.369
	25429.895		1087.519
V	30074.707		3895.783
Cr	< LOD	1	2941.619
Mn Fe	1774.087		884.326
Co	< LOD < LOD	1	825.624 528.886
Ni	< LOD	E	803.459
Cu	\$84054.125		4347.006
Zn	< LOD	- 5	1008.846
Se	420,590		145.992
Br	123.727	- 2	46.674
Zr	< LOD	1	149.853
Nb	< LOD	1 8	211.061
Ma	< LOD	÷	316.989
Pd	< LOD	(B	97,486
Ag	13931.646		426.177
Al	< LOD		800000.000
In	< LOD		320.257
Sn	210322.938	*	3037.189
Sb	< LOD	1	342.643
Ba	15896.746		841.507
W	< LOD		2.000
Pt	< LOD		845.341
Au	< LOD	1	644.901
Hg	< LOD		380.079
TI	115684.547	÷ .	6827.620
Bi	< LOD	1.1	460.478
	200		100.110

Supervised by: AAA Test Lab Inc

XRF Results - Sample 1

XRF Inspection (Continued)

Certificate of Verification

leading	No	6039	
Mode		Electroni	ics Metals
Time		2018-07	-18 10:09
Duration	1	61.52	
Units		ppm	
Sigma V	/alue	2	
Sequence	ce .	Final	
Alloy1			h : *7.50
Result		Fuil	
Flags			
SAMPLE			-BASOBIG
HEAT			agy Solutions
LOT		W18071	20002
BATCH			
MISC		JL .	
NOTE		Sample :	2
	2244		2007
	ppm		Error
Cd	< LOD	12	293,568
Pb	26288.801		1082.657
v	29743.000		3827.678
Čr .	< LOD		2843,168
Mn	< LOD	Ę	1712.735
Fe	< LOD	÷	795.535
Ca	< LOD		544.359
Ni	< LOD	1	829,471
Cu	577271.063	i i	4278.825
Zn	< LOD	1	966.403
Se	402,030		143,407
Br	< LOD		98.744
Zr	< LOD		141.421
Nb	< LOD	1	203.859
Ma	< LOD		315.551
Pd	< LOD	1	99.916
Ag	19907.537		516.302
AL	< LOD	-	800000.000
In	< LOD	- E	311.258
Sn	203922.703		2925,829
Sb	< LOD	12	345.772
Ba	13801.529		800,102
W	< LOD		2,000
Pt	< LOD	1. 1. 1.	858.251
Au	< 100	- C	568.085
Hg	< LOD	1	472.463
Ti	125219.094		6760.089
Bi	< LOD	1 3	502.915

Supervised by: AAA Test Lab Inc

XRF Results - Sample 2

Shipping			
Carrier	UPS	Service	Worldwide Expedited

N. 9 Approved by :

Gary Heyes General Manager